

FPGA Dynamic Probe Application for MSOs

Give your scope the ability to make rapid internal FPGA measurements



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Agilent's MSO FPGA dynamic probe provides internal FPGA visibility and quick instrument setup using an innovative core-assisted approach. Measurement tasks that previously took hours can be done in a few mouse clicks. In a few seconds you can easily measure a different set of internal signals without changing FPGA design.

FPGA dynamic probe for Xilinx and Altera FPGAs

The FPGA dynamic probe used in conjunction with an Agilent MSO provides an effective solution for debugging systems incorporating Xilinx and Altera FPGAs.

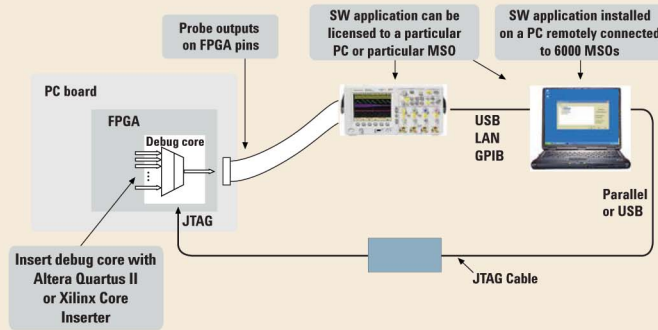
- Quickly access internal FPGA signal
- Automate MSO signal naming with names from the design environment
- Measure new group of signals in seconds
- Add and remove debug core without modifying original HDL code



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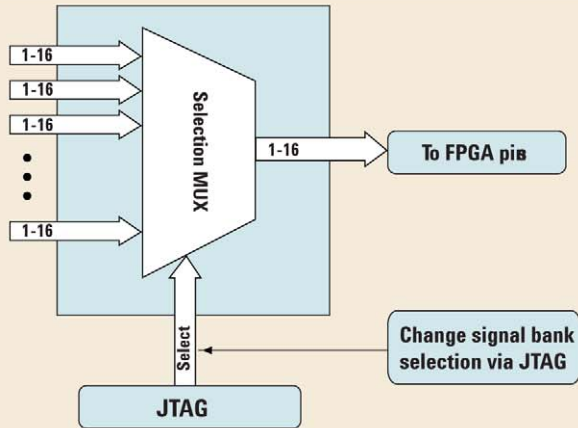
Create a time-saving FPGA measurement system.

Insert debug core into your FPGA design, with the application running on your PC you control which group of internal signals to measure via JTAG.



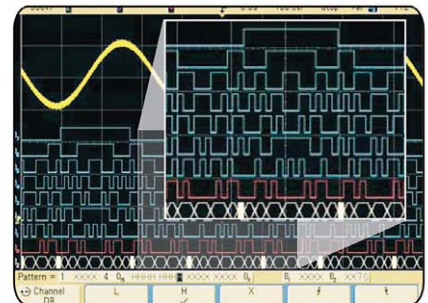
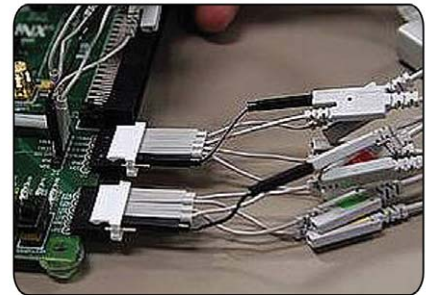
Access multiple internal signals for each debug pin

Signal banks all have identical width (1 to 16 signals wide) determined by the number of device pins you devote for debug. Each pin provides sequential access to one signal from every input bank.



Ordering information

Model number	Description
N5406A	InfiniiVision Series MSO FPGA dynamic probe application for Xilinx
N5434A	InfiniiVision Series MSO FPGA dynamic probe application for Altera
N5433A	MSO8000 FPGA dynamic probe application
N5397A	MSO8000 FPGA dynamic probe application



For more information:
www.agilent.com/find/FPGA
 1-800-829-4444

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